

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI40-273		SERIAL NO.	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT James E. O'Toole			
					FILING DATE February 11, 2000		GROUP 2681	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
M	AA	3,299,424	1/67	Vinding	-	-		
N	AB	3,852,755	12/74	Works et al.	-	-		
R	AC	4,075,632	2/21/78	Baldwin et al.	-	-		
N	AD	4,572,976	2/25/86	Fockens	-	-		
M	AE	4,656,463	4/7/87	Anders et al.	-	-		
N	AF	4,700,179	10/87	Fancher	-	-		
N	AG	4,724,427	2/9/88	Carroll	-	-		
N	AH	4,743,864	5/88	Nakagawa et al.	-	-		
N	AI	4,800,543	1/89	Lyndon-James et al.	-	-		
	AJ							
	AK							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
M	AR		"Micron Morning Report", The Idaho Statesman, July 16, 1993.					
N	AS		"A Low-Power Spread Spectrum CMOS RFIC for Radio Identification Applications", by John R. Tuttle, Conference					
			Proceedings from RF Expo West, pp. 216-222, March 22-24, 1994, San Jose, CA.					
N	AT		Provisional Application, Serial No. 60/023,321, Filed July 30, 1996.					
EXAMINER P. Sobushu				DATE CONSIDERED 6/18/01				
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>								












Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI40-273		SERIAL NO. 09/502643	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT James E. O'Toole			
					FILING DATE February 11, 2000		GROUP 2684	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
W	AA	4,816,839	Landt	—	—			
W	AB	4,827,395	Anders et al.	—	—			
W	AC	4,853,705	Landt	—	—			
W	AD	4,854,328	Pollack	—	—			
W	AE	4,857,893	Carroll	—	—			
W	AF	4,862,160	Ekchian et al.	—	—			
W	AG	4,870,419	Baldwin et al.	—	—			
W	AH	4,888,591	Landt et al.	—	—			
W	AI	4,890,072	Espe et al.	—	—			
W	AJ	4,912,471	Tyburski et al.	—	—			
W	AK	4,926,182	Ohta et al.	—	—			
FOREIGN PATENT DOCUMENTS								
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	AL							
	AM							
	AN							
	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
W	AR	"CMOS Analog Integrated Circuits Based on Weak Inversion Operation", by Eric Vittoz and Jean Fellrath, IEEE Journal of						
		Solid State Circuits, Vol. SC-12, No. 3, June 1977						
W	AS	Mitsubishi Motors Corporation Web Page, 1995						
W	AT	"Digital RF/ID Enhances GPS", by John R. Tuttle, Proceedings of the Second Annual Wireless Symposium, pp.406-411,						
		February 15-18, 1994, Santa Clara, CA						
EXAMINER P. Sabur				DATE CONSIDERED 6/18/01				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI40-273	SERIAL NO. 07/502693			
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT James E. O'Toole				
				FILING DATE February 11, 2000	GROUP 2687			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
W	AA	5,030,807	7/91	Landt et al.	—	—		
W	AB	5,075,691	12/91	Garay et al.	—	—		
W	AC	5,081,458	1/92	Meunier	—	—		
W	AD	5,086,389	2/4/92	Hassett et al.	—	—		
W	AE	5,122,687	6/92	Schmidt	—	—		
W	AF	5,128,938	7/92	Borras	—	—		
W	AG	5,130,668	7/92	Emslie et al.	—	—		
W	AH	5,134,085	7/28/92	Gilgen et al.	—	—		
W	AI	5,142,292	8/92	Chang	—	—		
W	AJ	5,144,314	9/1/92	Malmberg et al.	—	—		
W	AK	5,151,624	9/92	Stegherr et al.	—	—		
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	AM							
	AN							
	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
W	AR		Provisional Application, Serial No. 60/023,318, Filed July 30, 1996.					
W	AS		"Micron RFID Communications Protocol Manual," July 22, 1993, Pre-Release Version 0.95, pp. 1-71.					
	AT							
EXAMINER				DATE CONSIDERED				
P. S. O'Brien				6-18-07				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI40-273		SERIAL NO. 04/502673	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT James E. O'Toole			
					FILING DATE February 11, 2000		GROUP 2087	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
AA	5,153,583	10/92	Murdoch					
AB	5,164,985	11/17/92	Nysen et al.					
AC	5,175,774	12/29/92	Truax et al.					
AD	5,206,609	4/27/93	Mijuskovic					
AE	5,218,343	6/8/93	Stobbe et al.					
AF	5,231,273	7/93	Caswel					
AG	5,252,979	10/12/93	Nysen					
AH	5,272,367	12/21/93	Dennison et al.					
AI	5,287,112	2/15/94	Schuermann					
AJ	5,294,928	3/15/94	Cooper et al.					
AK	5,300,875	4/5/89	Tuttle					
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER P. Shukla				DATE CONSIDERED 6/18/07				
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI40-273		SERIAL NO.	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT James E. O'Toole			
					FILING DATE February 11, 2000		GROUP	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
✓	AA	5,311,186	Utsu et al.	—	—			
✓	AB	5,323,150	Tuttle	—	—			
✓	AC	5,355,513	Clarke et al.	—	—			
✓	AD	5,365,551	Snodgrass et al.	—	—			
✓	AE	5,374,930	Schuermann	—	—			
✓	AF	5,394,444	Silvey et al.	—	—			
✓	AG	5,406,263	Tuttle	—	—			
✓	AH	5,412,351	Nystrom et al.	—	—			
✓	AI	5,420,757	Eberhardt et al.	—	—			
✓	AJ	5,430,441	Bickley et al.	—	—			
✓	AK	5,444,223	Blama	—	—			
FOREIGN PATENT DOCUMENTS								
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EXAMINER D. Schurman				DATE CONSIDERED 6/18/02				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI40-273	SERIAL NO. 09/502693		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT James E. O'Toole			
				FILING DATE February 11, 2000	GROUP 2684		
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>[initials]</i>	AA	5,446,761	8/95	Nag et al.	<i>[initials]</i>		
<i>[initials]</i>	AB	5,448,110	9/95	Tuttle et al.	<i>[initials]</i>		
<i>[initials]</i>	AC	5,448,242	9/5/95	Sharpe et al.	<i>[initials]</i>		
<i>[initials]</i>	AD	5,448,772	9/95	Grandfield	<i>[initials]</i>		
<i>[initials]</i>	AE	5,450,087	9/95	Horta et al.	<i>[initials]</i>		
<i>[initials]</i>	AF	5,461,385	10/24/95	Armstrong	<i>[initials]</i>		
<i>[initials]</i>	AG	5,471,212	11/28/95	Sharpe et al.	<i>[initials]</i>		
<i>[initials]</i>	AH	5,478,991	12/95	Watanabe et al.	<i>[initials]</i>		
<i>[initials]</i>	AI	5,489,546	2/6/96	Ahmad et al.	<i>[initials]</i>		
<i>[initials]</i>	AJ	5,499,214	3/96	Mori et al.	<i>[initials]</i>		
<i>[initials]</i>	AK	5,500,650	3/19/96	Snodgrass et al.	<i>[initials]</i>		
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER <i>D. Sobotha</i>				DATE CONSIDERED <i>6/18/04</i>			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT James E. O'Toole			
					FILING DATE February 11, 2000		GROUP 2C89	
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	AA	5,525,992	Froschermeier	—	—			
	AB	5,541,583	Mandelbaum	—	—			
	AC	5,541,585	Dubame et al.	—	—			
	AD	5,568,512	Rotzoll	—	—			
	AE	5,606,323	Heinrich et al.	—	—			
	AF	5,621,412	Sharpe et al.	—	—			
	AG	5,623,224	Yamada et al.	—	—			
	AH	5,649,296	MacLellan et al.	—	—			
	AI	5,657,359	Sakae et al.	—	—			
	AJ	5,677,667	Lesesky et al.	—	—			
	AK	5,686,864	Martin et al.	—	—			
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EXAMINER P. Sibuth				DATE CONSIDERED 6/18/07				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI40-273

SERIAL NO.

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LIST OF ART CITED BY APPLICANT
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James E. O'TooleFILING DATE
February 11, 2000

GROUP 2087

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
W	AA	5,686,920	11/11/97	Hurta et al.	-	-	
W	AB	5,703,509	12/97	Hirata	-	-	
W	AC	5,719,550	2/17/98	Bloch et al.	-	-	
W	AD	5,721,678	2/24/98	Widl	-	-	
W	AE	5,721,783	2/98	Anderson	-	-	
W	AF	5,726,630	3/10/98	Marsh et al.	-	-	
W	AG	5,815,042	9/98	Chow et al.	-	-	
W	AH	5,901,349	5/99	Guegnaud et al.	-	-	
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FOREIGN PATENT DOCUMENTS

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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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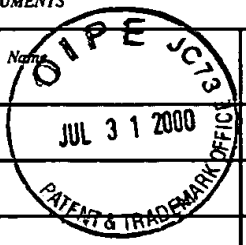
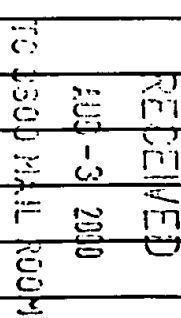
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI40-273	SERIAL NO. 09/502693			
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT James E. O'Toole et al.				
				FILING DATE February 11, 2000	GROUP 2654			
U.S. PATENT DOCUMENTS								
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~	AA	4,746,830	5/24/88	Holland	—	—		
~	AB	4,786,903	11/22/88	Grindahl et al.	—	—		
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER P. Sebuthe				DATE CONSIDERED 6/18/04				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

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Form PTO-145		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M140-273		SERIAL NO. 09/502,693	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Micron Technology, Inc.			
					FILING DATE February 11, 2000		GROUP 3662 2657	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
✓	AA	5,191,295	03/02/93 Necoechea	328	155	 <div style="position: absolute; top: 0; right: 0; text-align: right;"> RECEIVED NOV 02 2000 Technology Center 2600 </div>		
✓	AB	5,281,927	01/25/94 Parker	331	1 A			
✓	AC	5,576,647	11/19/96 Sutardja et al.	327	108			
✓	AD	5,774,022	06/30/98 Griffin et al.	331	1 A			
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FOREIGN PATENT DOCUMENTS								
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER <i>P. S. abv. My</i>				DATE CONSIDERED <i>6/18/04</i>				
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI40-273		SERIAL NO. 09/502,693	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT James E. O'Toole et al.			
				FILING DATE February 11, 2000		GROUP 3662	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if appropriate
~	AA	4,952,889	8/28/90	Irwin et al.	1	1	
~	AB	5,412,665	5/2/95	Gruodis et al.	1	1	
~	AC	5,416,421	5/16/95	Kootstra et al.	1	1	
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FOREIGN PATENT DOCUMENTS							
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							Yes No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER P. Sobu/ku				DATE CONSIDERED 6/18/07			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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PATENT & TRADEMARK OFFICE

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Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI40-273SERIAL NO.
09/502,693LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
James E. O'Toole et al.FILING DATE
February 11, 2000GROUP
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U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
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FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
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	AM							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

✓	AR		Analysis and Design of Analog Integrated Circuits, Paul R. Gray & Robert G. Meyer, pages 667-681; 1993.					
✓	AS		Analog Integrated Circuits for Communication (Principles, Simulation and Design), Donald O. Pederson & Kartikeya Mayaram, pages 431-433, 1991.					
✓	AT		A Precise Four-Quadrant Multiplier With Subnanosecond Response, B. Gilbert, IEEE Journal of Solid State Circuits, pages 365-373, 1968.					

EXAMINER

P. Sobutka

DATE CONSIDERED

6/18/07

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#8

Form PTO-119 OFFICE DEC 18 2000 PATENT & TRADEMARK OFFICE		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M140-273		SERIAL NO. 09/502,693	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.		FILING DATE February 11, 2000	
				GROUP 3602		2687	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
n	AA	5,340,968	8/23/94	Watanabe et al.			
	AB						
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EXAMINER				DATE CONSIDERED			
Philip Sabuk				6/18/07			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-117 <div style="border: 1px solid black; border-radius: 50%; padding: 10px; display: inline-block; text-align: center;"> O.T.P.E. FEB 20 2001 </div>		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI40-273		SERIAL NO. 09/502,693	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.		FILING DATE February 11, 2000	
				GROUP 2685			
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
W	AA	5,907,789	Komatsu				
W	AB	5,780,916	Berger et al.				
W	AC	3,924,320	Altman et al.				
	AD						
	AE						
	AF						
	AG						
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	AI						
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR		Muller & Kamins, DEVICE ELECTRONICS FOR INTEGRATED CIRCUITS, 1977, John Wiley & Sons, 2 nd Edition, Pages 157-160.				
	AS		Fink & Christiansen, ELECTRONICS ENGINEER'S HANDBOOK, 1989, McGraw-Hill Book Company, 3 rd Edition, Pages 7-41 to 7-42, 8-38 to 8-39, and 9-66 to 6-69.				
	AT						
EXAMINER				DATE CONSIDERED			
P. Subuthe				6/18/04			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI40-273SERIAL NO.
09/502,693LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
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U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA					
	AB					
	AC					
	AD					
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	AK					

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AR		Raymond W. Waugh, "Designing Detectors for RF/ID Tags," Proceedings of RF Expo West, 1995, 13 pages.
	AS		
	AT		

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DATE CONSIDERED

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Sheet 1 of 1

#13

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI40-273		SERIAL NO. 09/502,693	
<div style="text-align: center;"> LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) </div>				APPLICANT Micron Technology, Inc.		FILING DATE February 11, 2000	
				GROUP 3662 2687			
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
n	AA 5,361,403	11/1994	Dent	455	74		
n	AB 5,423,074	06/1995	Dent	455	74		
~	AC 4,783,646	11.1988	Matsuzaki	340	572		
~	AD 5,072,194	12/1991	Chevallier	330	260		
~	AE 5,300,896	04/1994	Suesserman	330	260		
~	AF 5,365,192	11/1994	Wagner et al.	330	252		
~	AG 5,394,159	02/1995	Schneider et al.	343	700		
~	AH 4,190,838	02/1980	Kemp	343	18		
~	AI 5,511,090	04/1996	Denton et al.	375	205		
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
n	AL 0 172 445 A1	07/1985	EPO				x
n	AM 0 682 382 A2	04/1995	EPO			x	
~	AN 0 682 382 A3	05/1995	EPO			x	
	AO DB-3212876 A1	04/1985	Germany				x
	AP 0-646-429 A1	07/1994	EPO				x
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
n	AR	N.J. Woods et al., "One micrometre scale self-aligned cobalt disilicide Schottky barrier diodes", ELECTRONICS LETTERS, IEE Stevenage, GB, Vol. 31, No. 21, Oct. 1995, pages 1878-1880					
n	AS	Shenai Krishna, "Characteristics of LPCVD WS12/N-Si Schottky Contacts", IEEE ELECTRON DEVICE LETTERS, US, IEEE INC. N.Y., Vol. 12 No. 4, April 1991, pages 169-171					
	AT						
EXAMINER P. Sobushka				DATE CONSIDERED 6/18/07			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

#14

Form PTO-1449

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PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M140-273SERIAL NO.
09/502,693LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
James E. O'Toole et al.FILING DATE
February 11, 2000GROUP
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U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
~	AA	5,446,765	08/29/95	LEGER	375	359	
~	AB	5,668,560	09/16/97	EVANS ET AL.	343	702	
~	AC	5,940,006	08/17/99	MacLELLAN ET AL.	340	825.54	
~	AD	5,970,398	10/19/99	TUTTLE	455	193.1	
~	AE	6,122,494	09/19/00	TUTTLE	455	193.1	
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	AI						
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FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
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	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

~	AR	BUECHLER, J., et al., "Silicon Millimeter-Wave Circuits for Receivers and Transmitters", IEEE MICROWAVE AND MILLIMETER-WAVE MONOLITHIC CIRCUITS SYMPOSIUM, pp. 67-70 (1988)
~	AS	WOLF Ph.D., STANLEY, "Silicon Processing for the VLSI Era, Volume 2: Process Integration", Lattice Press, pp. 65 & 195 (1990)
	AT	

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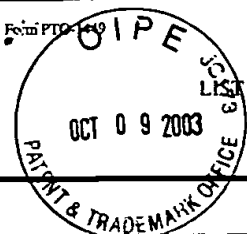
P. Schubert

DATE CONSIDERED

6/18/07

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#15

Form PTO-149		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI40-273		SERIAL NO. 09/502,693		
				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				
				APPLICANT James E. O'Toole et al.		FILING DATE February 11, 2000		
				GROUP 3002 2687				
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
~	AA	4,897,662	01/30/90	Lee et al.	343	701		
~	AB	4,942,393	07/17/90	Waraksa et al.	340	825.72		
~	AC	5,235,326	08/10/93	Beigel et al.	340	825.54		
~	AD	5,317,309	05/31/94	Vercellotti et al.	340	825.54		
~	AE	5,519,386	05/21/96	Tobergte	340	825.54		
~	AF	5,649,295	07/15/97	Shober et al.	455	38.2		
~	AG	6,249,212 B1	06/19/01	Beigel et al.	340	10.34		
~	AH	5,491,718	02/13/96	Gould et al.	375	205		
~	AI	5,606,322	02/25/97	Allen et al.	341	173		
	AJ							
	AK							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
~	AL	2 238 210 A	05/1991	Great Britain			x	
	AM							
	AN							
	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
	AT							
EXAMINER				DATE CONSIDERED				
P. Sobel				6 / 18 / 01				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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